# International Rectifier

## **IRF9540N**

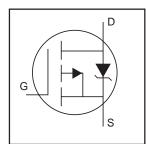
#### HEXFET® Power MOSFET

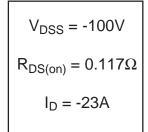
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated

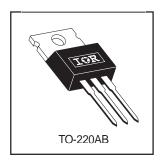
#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-23		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-10V -16		
I <sub>DM</sub>	Pulsed Drain Current ①	-76		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	140	W	
	Linear Derating Factor	0.91	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>②</sup>	430	mJ	
I <sub>AR</sub>	Avalanche Current①	-11	А	
E <sub>AR</sub>	Repetitive Avalanche Energy®	14	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns	
T <sub>J</sub>	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )		
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)		

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.1	
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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## Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	•	-				
	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-100			V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.11		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.117	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -11A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$
9 <sub>fs</sub>	Forward Transconductance	5.3			S	$V_{DS} = -50V, I_{D} = -11A$
l	Drain-to-Source Leakage Current			-25	μA	$V_{DS} = -100V, V_{GS} = 0V$
I <sub>DSS</sub>	Brain to Godice Leakage Current			-250	μΑ	$V_{DS} = -80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			97		I <sub>D</sub> = -11A
Q <sub>gs</sub>	Gate-to-Source Charge			15	nC	$V_{DS} = -80V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			51		$V_{GS}$ = -10V, See Fig. 6 and 13 $\oplus$
t <sub>d(on)</sub>	Turn-On Delay Time		15			$V_{DD} = -50V$
t <sub>r</sub>	Rise Time		67			$I_{D} = -11A$
t <sub>d(off)</sub>	Turn-Off Delay Time		51		ns	$R_G = 5.1\Omega$
t <sub>f</sub>	Fall Time		51			$R_D = 4.2\Omega$ , See Fig. 10 $\oplus$
L <sub>D</sub>	Internal Drain Inductance		4.5		- nH	Between lead,
	mona Dian madalans					6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5			from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		1300			$V_{GS} = 0V$
Coss	Output Capacitance		400		pF	$V_{DS} = -25V$
$C_{rss}$	Reverse Transfer Capacitance		240			f = 1.0MHz, See Fig. 5

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-23		MOSFET symbol
	(Body Diode)	-	-23	A	showing the	
I <sub>SM</sub>	Pulsed Source Current			70		integral reverse
	(Body Diode) ①		76	-/6	p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			-1.6	V	$T_J = 25$ °C, $I_S = -11A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		150	220	ns	$T_J = 25^{\circ}C, I_F = -11A$
Q <sub>rr</sub>	Reverse RecoveryCharge		830	1200	nC	di/dt = -100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25^{\circ}C$ , L = 7.1mH $R_G = 25\Omega$ ,  $I_{AS} = -11A$ . (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq \text{-}11A, \text{ } di/dt \leq \text{-}470A/\mu s, \text{ } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}C \end{array}$
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .



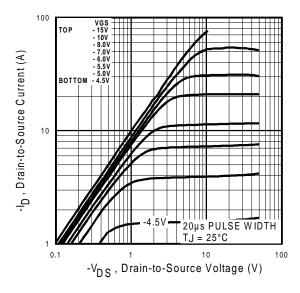


Fig 1. Typical Output Characteristics

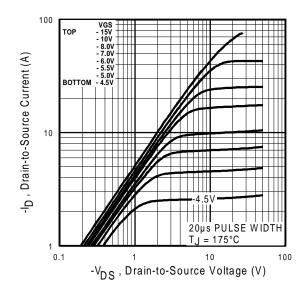


Fig 2. Typical Output Characteristics

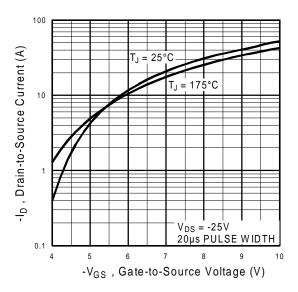
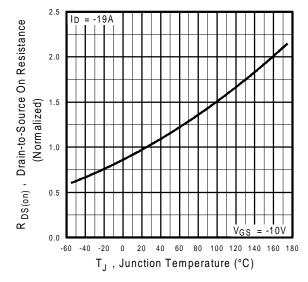
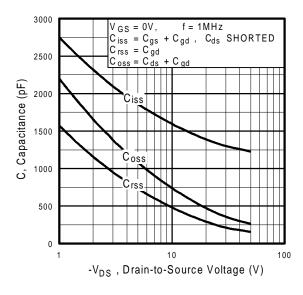


Fig 3. Typical Transfer Characteristics

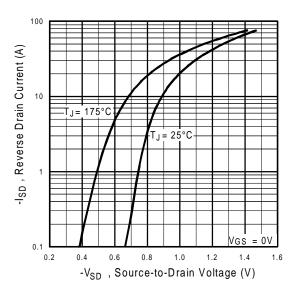


**Fig 4.** Normalized On-Resistance Vs. Temperature

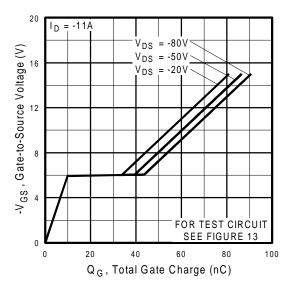
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**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

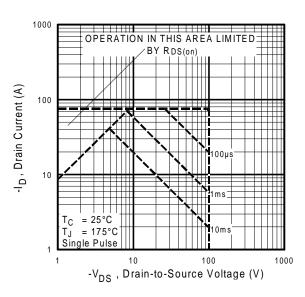
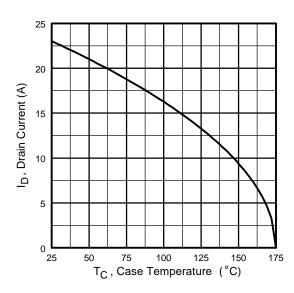


Fig 8. Maximum Safe Operating Area



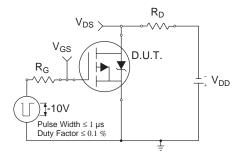
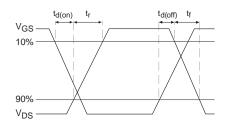


Fig 10a. Switching Time Test Circuit



**Fig 9.** Maximum Drain Current Vs. Case Temperature

Fig 10b. Switching Time Waveforms

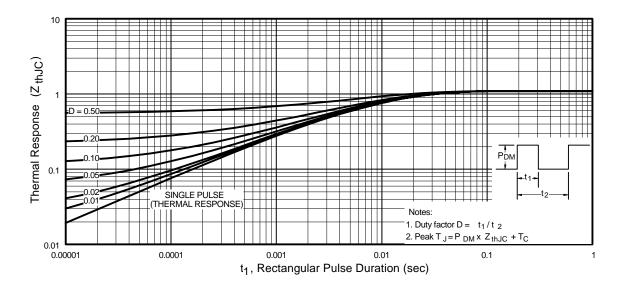


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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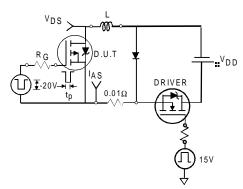


Fig 12a. Unclamped Inductive Test Circuit

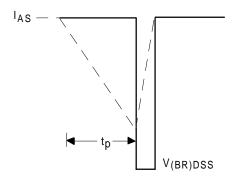


Fig 12b. Unclamped Inductive Waveforms

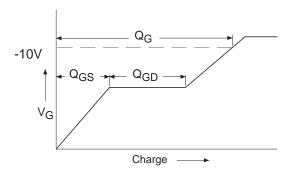
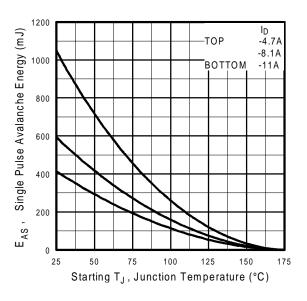


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

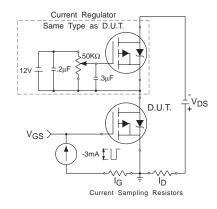
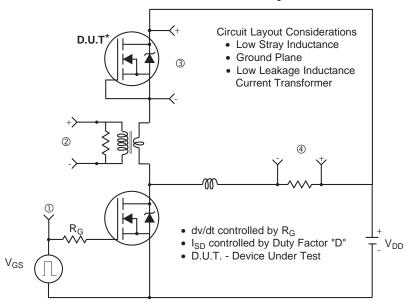
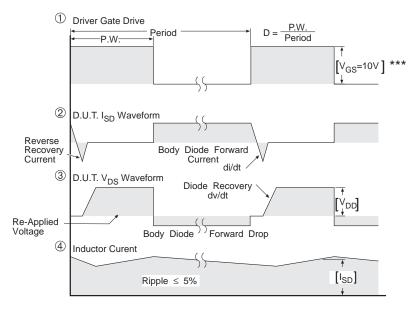


Fig 13b. Gate Charge Test Circuit

### Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



\*\*\* V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

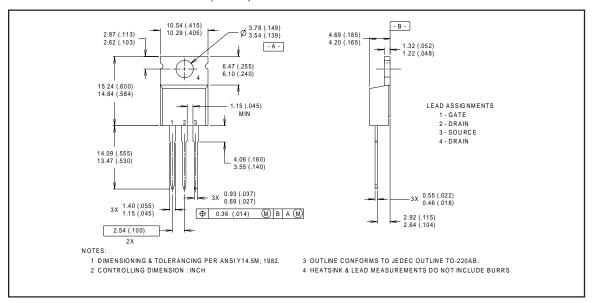
Fig 14. For P-Channel HEXFETS

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#### Package Outline

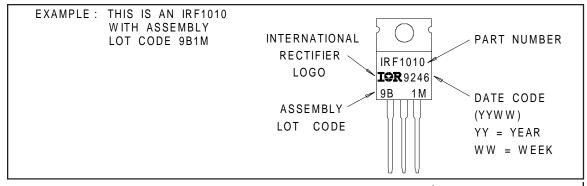
#### TO-220AB Outline

Dimensions are shown in millimeters (inches)



### Part Marking Information

#### **TO-220AB**



## Internationa Rectifier

WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331
EUROPEAN HEADQUARTERS: Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44 1883 732020
IR CANADA: 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897
IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590
IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111
IR FAR EAST: K&H Bldg., 2F, 30-4 Nishi-Ikebukuro 3-Chome, Toshima-Ku, Tokyo Japan 171 Tel: 81 3 3983 0086

IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371

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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>